

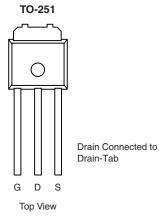
HY70R751U-VB Datasheet **Power MOSFET**

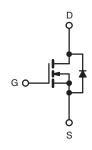
PRODUCT SUMMARY					
V _{DS} (V)	700				
R _{DS(on)} (Ω)	V _{GS} = 10 V 1.9				
Q _g (Max.) (nC)	130				
Q _{gs} (nC)	17				
Q _{gd} (nC)	72				
Configuration	Single				

FEATURES

- Dynamic dV/dt rating
- Repetitive avalanche rated
- Isolated central mounting hole
- · Fast switching
- Ease of paralleling
- Simple drive requirements







N-Channel MOSFET

PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	700	V	
Gate-Source Voltage			V _{GS}	± 20	V	
Continuous Drain Current	$V_{GS} \text{ at } 10 \text{ V} \qquad \frac{T_{C} = 25 \text{ °C}}{T_{C} = 100 \text{ °C}}$		6.0			
	VGS at 10 V	T _C = 100 °C	ID	4.2	А	
Pulsed Drain Current ^a			I _{DM}	24		
Linear Derating Factor				1.2	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	490	mJ	
Repetitive Avalanche Current ^a			I _{AR}	5.4	А	
Repetitive Avalanche Energy ^a			E _{AR}	15	mJ	
Maximum Power Dissipation	T _C = 25 °C		PD	150	W	
Peak Diode Recovery dV/dt ^c			dV/dt	2.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55 to +150	°C	
Soldering Recommendations (Peak Temperature) ^d	for	10 s	-	300		
Mounting Torque	6-32 or M3 screw			10	lbf ∙ in	
Mounting Torque				1.1	N · m	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. $V_{DD} = 50$ V, starting $T_J = 25$ °C, L = 31 mH, $R_g = 25 \Omega$, $I_{AS} = 5.4$ A (see fig. 12). c. $I_{SD} \le 5.4$ A, dl/dt ≤ 120 A/µs, $V_{DD} \le 600$, $T_J \le 150$ °C.

d. 1.6 mm from case.



THERMAL RESISTANCE RATINGS						
PARAMETER	SYMBOL	TYP.	MAX.	UNIT		
Maximum Junction-to-Ambient	R _{thJA}	-	40			
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W		
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.83			

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static		*			•	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$) V, I _D = 250 μA	700	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	to 25 °C, I _D = 1 mA	-	0.98	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}		/ _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}		$_{iS} = \pm 20 \text{ V}$		_	± 100	nA
Gate Source Loundye	-033	$V_{DS} = 700 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	_	100	μA
Zero Gate Voltage Drain Current	I _{DSS}		$V_{DS} = 760 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$ $V_{DS} = 560 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 125 \text{ °C}$		-	500	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 3.2 A ^b	_	1.9	-	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 10	00 V, I _D = 3.2 A ^b	3.0	-	-	S
Dynamic		•				•	
Input Capacitance	C _{iss}	V	$V_{GS} = 0 V_{.}$	-	1900	-	pF
Output Capacitance	C _{oss}		$_{DS} = 25 V,$	-	470	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0	MHz, see fig. 5	-	280	-	
Total Gate Charge	Qg			-	-	130	
Gate-Source Charge	Q _{gs}	V _{GS} = 10 V	$V_{GS} = 10 V$ $I_D = 5.4 A, V_{DS} = 350 V,$		-	17	nC
Gate-Drain Charge	Q _{gd}		see fig. 6 and 13 ^b	-	-	72	1
Turn-On Delay Time	t _{d(on)}			-	16	-	
Rise Time	t _r	- V_D = 3	V_{DD} = 350 V, I _D = 5.4 A, R _g = 9.1 Ω, R _D = 75 Ω, see fig. 10 ^b		36	-	- ns
Turn-Off Delay Time	t _{d(off)}	$R_g = 9.1 \Omega, R_f$			100	-	
Fall Time	t _f			-	32	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	
Internal Source Inductance	Ls			-	13	-	nH
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	5.4	Α
Pulsed Diode Forward Current ^a	I _{SM}			-	-	22	A
Body Diode Voltage	V _{SD}	T _J = 25 °C, Is	$_{\rm S}$ = 5.4 A, V _{GS} = 0 V ^b	-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 5.4 A, dl/dt = 100 A/µs ^b		-	550	830	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	2.4	3.6	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				L _D)	

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width \leq 300 $\mu s;$ duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

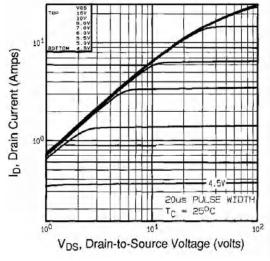


Fig. 1 - Typical Output Characteristics, $T_C = 25 \ ^{\circ}C$

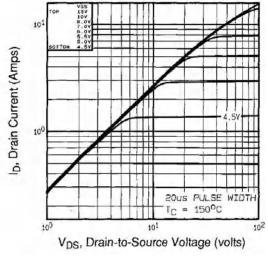


Fig. 2 - Typical Output Characteristics, $T_C = 150$ °C

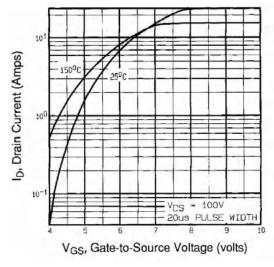


Fig. 3 - Typical Transfer Characteristics

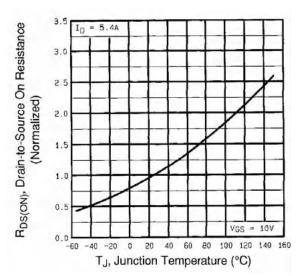


Fig. 4 - Normalized On-Resistance vs. Temperature

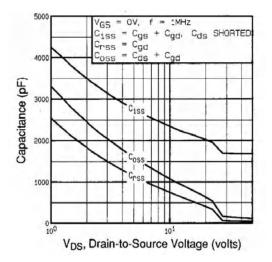
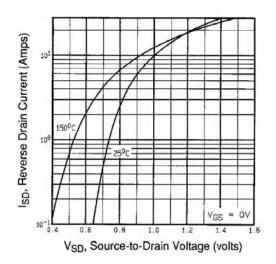


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage



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Fig. 7 - Typical Source-Drain Diode Forward Voltage

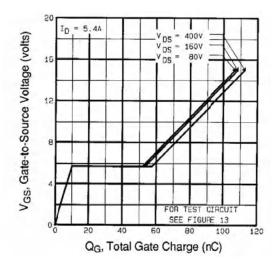


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

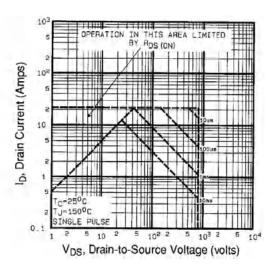


Fig. 8 - Maximum Safe Operating Area

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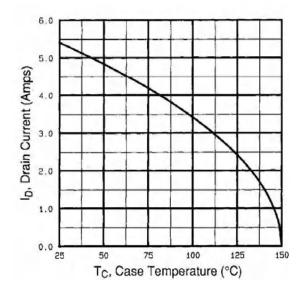


Fig. 9 - Maximum Drain Current vs. Case Temperature

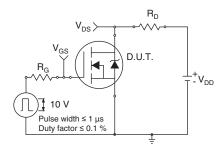


Fig. 10a - Switching Time Test Circuit

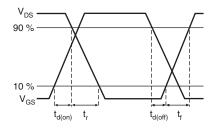


Fig. 10b - Switching Time Waveforms

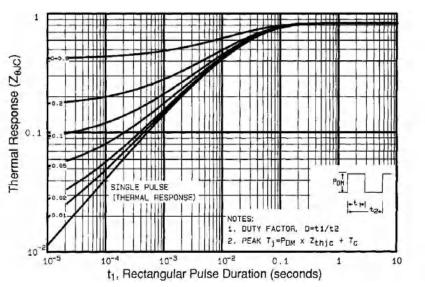


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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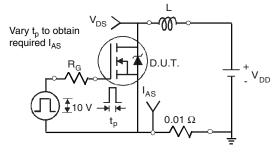


Fig. 12a - Unclamped Inductive Test Circuit

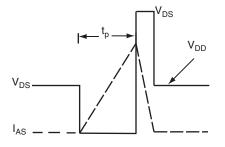


Fig. 12b - Unclamped Inductive Waveforms

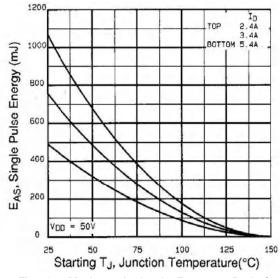
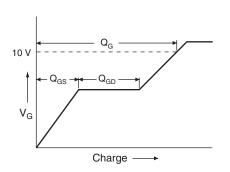


Fig. 12c - Maximum Avalanche Energy vs. Drain Current



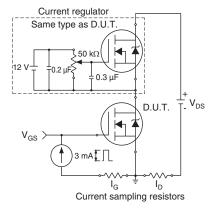
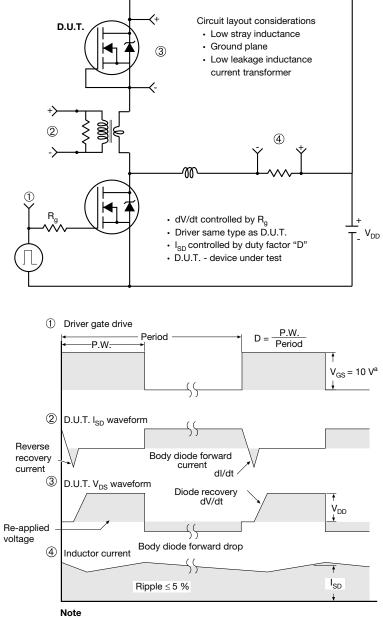


Fig. 13a - Basic Gate Charge Waveform





Peak Diode Recovery dV/dt Test Circuit

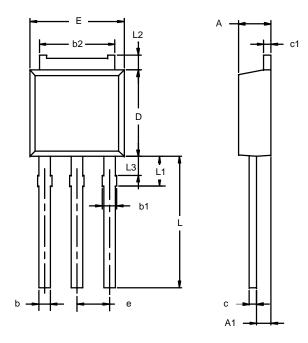


a. V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel



TO-251AA (DPAK)



	MILLIM	IETERS	INC	HES	
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
c1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
E	6.48	6.73	0.255	0.265	
е	2.28	BSC	0.090	BSC	
L	3.89	9.53	0.153	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	

Note: Dimension L3 is for reference only.



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